**FAIRCHILD** 

## 30V P-Channel PowerTrench<sup>®</sup> MOSFET

## **General Description**

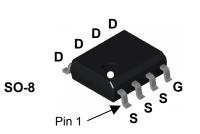
This P-Channel MOSFET is a rugged gate version of Fairchild Semiconductor's advanced PowerTrench process. It has been optimized for power management applications requiring a wide range of gave drive voltage ratings (4.5V - 25V).

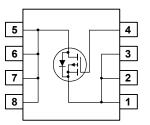
## Applications

- Power management
- Load switch
- Battery protection

## Features

- -5.3 A, -30 V  $R_{DS(ON)} = 50 \text{ m}\Omega @ V_{GS} = -10 \text{ V}$  $R_{DS(ON)} = 80 \text{ m}\Omega @ V_{GS} = -4.5 \text{ V}$
- Low gate charge
- · Fast switching speed
- High performance trench technology for extremely low  $R_{\text{DS}(\text{ON})}$
- High power and current handling capability





## Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol		Parameter		Ratings	Units	
V <sub>DSS</sub>	Drain-Source	urce Voltage		-30	V	
V <sub>GSS</sub>	Gate-Sourc	e Voltage		±25	V	
ID	Drain Current – Continuous (Note 1a)		(Note 1a)	-5.3	А	
		– Pulsed		-50		
PD	Power Diss	pation for Single Operation	(Note 1a)	2.5	W	
			(Note 1b)	1.2		
			(Note 1c)	1		
T <sub>J</sub> , T <sub>STG</sub>	Operating a	ing and Storage Junction Temperature Range		–55 to +175	°C	
Therma	I Charac	teristics				
R <sub>0JA</sub>	Thermal Re	sistance, Junction-to-Ambie	ent (Note 1a)	50	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note			125	°C/W	
R <sub>θJC</sub>	Thermal Resistance, Junction-to-Case (Note 1)			25 °(		
Packag	e Markin	g and Ordering Ir	nformation			
Device Marking		Device	Reel Size	Tape width	Quantity	

_	Device Marking	Device	Reel Size	Tape width	Quantity
-	NDS9435A	NDS9435A	13"	12mm	2500 units

©2002 Fairchild Semiconductor Corporation

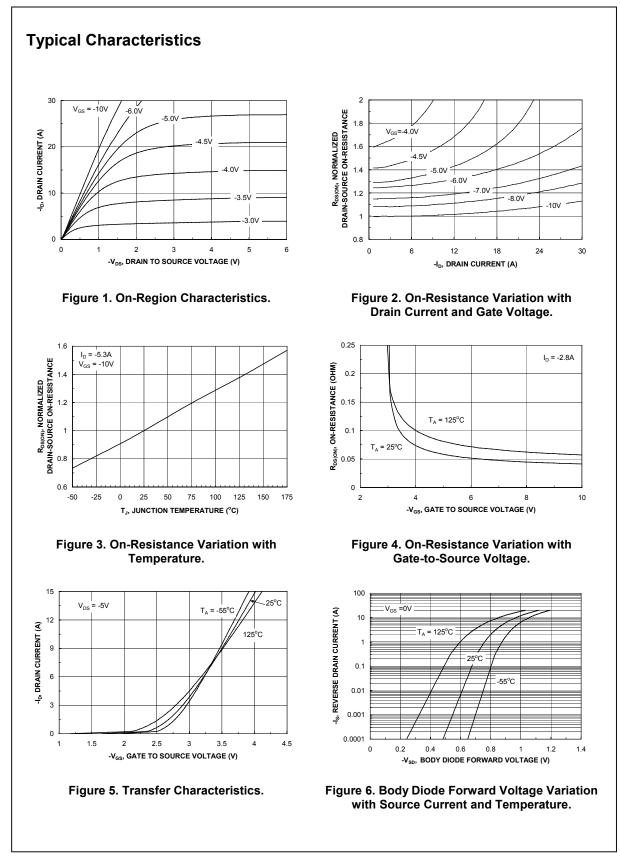
Symbol	Parameter	Test Conditions	Min	Тур	Мах	Units
Off Char	acteristics			l		I
BV <sub>DSS</sub>	Drain–Source Breakdown Voltage	$V_{GS}$ = 0 V, I <sub>D</sub> = -250 µA	-30			V
<u>ΔBV<sub>DSS</sub></u> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D = -250 \ \mu\text{A}$ , Referenced to 25°C		-23		mV/°C
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = -24 V$ , $V_{GS} = 0 V$			-1	μA
IGSSF	Gate-Body Leakage, Forward	$V_{GS} = 25 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I <sub>GSSR</sub>	Gate–Body Leakage, Reverse	$V_{GS} = -25 V$ $V_{DS} = 0 V$			-100	nA
On Char	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \ \mu A$	-1	-1.7	-3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D$ = -250 µA, Referenced to 25°C		4.5		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$ \begin{array}{ll} V_{GS} = -10 \ V, & I_D = -5.3 \ A \\ V_{GS} = -4.5 \ V, & I_D = -4 \ A \\ V_{GS} = -10 \ V, \ I_D = -5.3 \ A, \ T_J = 125^\circ C \end{array} $		42 65 57	50 80 77	mΩ
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = -10 \text{ V},  V_{DS} = -5 \text{ V}$	-25			Α
<b>g</b> <sub>FS</sub>	Forward Transconductance	$V_{DS} = -5 V$ , $I_{D} = -5.3 A$		10		S
Dynamic	Characteristics					
Ciss	Input Capacitance	$V_{DS} = -15 V$ , $V_{GS} = 0 V$ ,		528	Γ	pF
Coss	Output Capacitance	f = 1.0  MHz		132	ł – –	pF
Crss	Reverse Transfer Capacitance			70		pF
						μ.
	Turn–On Delay Time			7	14	
t <sub>d(on)</sub>	,					ns
t <sub>r</sub>	Turn–On Rise Time			13	24	ns
t <sub>d(off)</sub>	Turn–Off Delay Time	-		14	25	ns
t <sub>f</sub>	Turn–Off Fall Time			9	17	ns
Q <sub>g</sub>	Total Gate Charge	$V_{DS} = -15 V$ , $I_D = -4 A$ , $V_{GS} = -10 V$		10	14	nC
Q <sub>gs</sub>	Gate-Source Charge			2.2		nC
$Q_{gd}$	Gate–Drain Charge			2		nC
Drain-Se	ource Diode Characteristics			1	r	I
ls	Maximum Continuous Drain-Source	e Diode Forward Current			-2.1	Α
V <sub>SD</sub>	Drain–Source Diode Forward Voltage	$V_{GS} = 0 V$ , $I_S = -2.1 A$ (Note 2)		-0.8	-1.2	V
	n of the junction-to-case and case-to-ambient then $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is deter a) 50°C/W when	mal resistance where the case thermal reference i rmined by the user's board design. پ پ b) 105°C/W when	ų	as the sold	ler mounting	g surface o ited on a

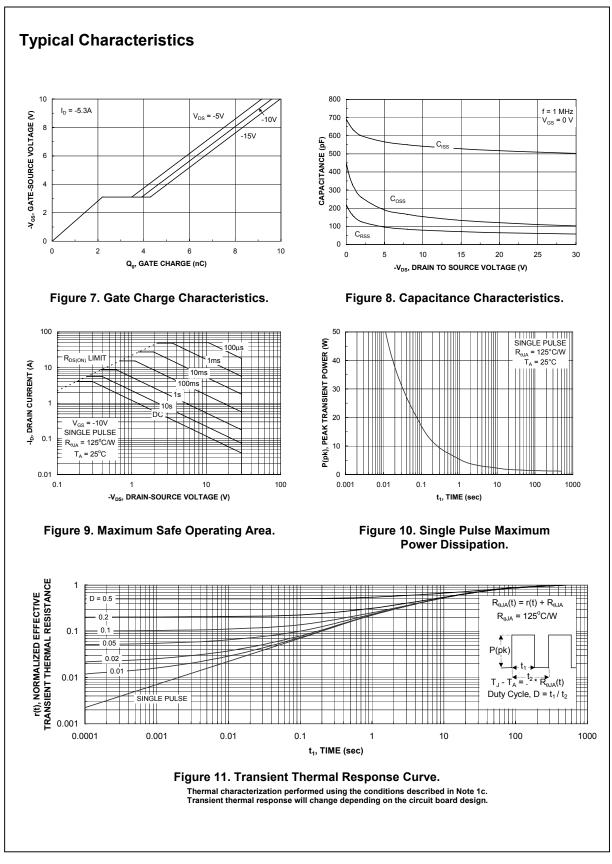


Scale 1 : 1 on letter size paper

**2.** Pulse Test: Pulse Width < 300 $\mu$ s, Duty Cycle < 2.0%

~~~~





NDS9435A Rev E(W)

### TRADEMARKS

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

ACEx™ Bottomless™ CoolFET™ CROSSVOLT™ DenseTrench™ DOME™ **EcoSPARK™** E<sup>2</sup>CMOS<sup>™</sup> EnSigna™ FACT™ FACT Quiet Series™ FAST ® FASTr™ FRFET™ GlobalOptoisolator<sup>™</sup> POP<sup>™</sup> GTO™ HiSeC™ ISOPLANAR™ LittleFET™ MicroFET™ MicroPak™ MICROWIRE™

**OPTOLOGIC™** OPTOPLANAR™ PACMAN™ Power247™ PowerTrench<sup>®</sup> QFET™ QS™ QT Optoelectronics<sup>™</sup> Quiet Series<sup>™</sup> SILENT SWITCHER®

SMART START™ VCX™ STAR\*POWER™ Stealth™ SuperSOT<sup>™</sup>-3 SuperSOT<sup>™</sup>-6 SuperSOT<sup>™</sup>-8 SyncFET™ TinyLogic™ TruTranslation<sup>™</sup> UHC™ UltraFET<sup>®</sup>

STAR\*POWER is used under license

## DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY. FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

## LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user.

2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

### **PRODUCT STATUS DEFINITIONS**

**Definition of Terms** 

| Formative or<br>In Design | This datasheet contains the design specifications for<br>product development. Specifications may change in<br>any manner without notice.                                                                                          |
|---------------------------|-----------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| First Production          | This datasheet contains preliminary data, and<br>supplementary data will be published at a later date.<br>Fairchild Semiconductor reserves the right to make<br>changes at any time without notice in order to improve<br>design. |
| Full Production           | This datasheet contains final specifications. Fairchild<br>Semiconductor reserves the right to make changes at<br>any time without notice in order to improve design.                                                             |
| Not In Production         | This datasheet contains specifications on a product<br>that has been discontinued by Fairchild semiconductor.<br>The datasheet is printed for reference information only.                                                         |
|                           | In Design<br>First Production<br>Full Production                                                                                                                                                                                  |